

## TLNC Nano profiler 80-633

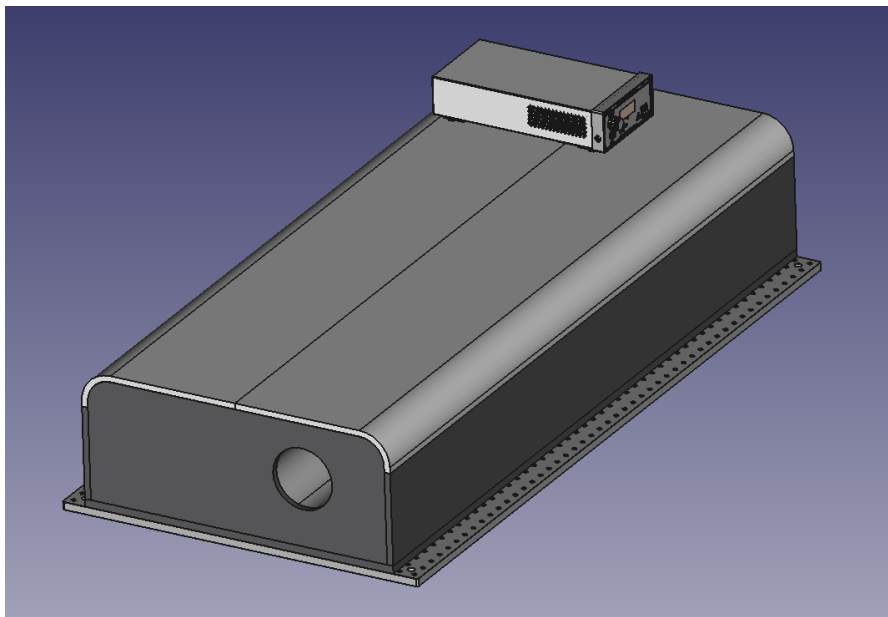
Trillinis Lab s.r.o offers a versatile non-contact system for swift optical components characterization. Primarily used for flat optical components (e.g. mirrors) our profiler measure surface profile in a single-shot operation with an accuracy of down to 200nm.

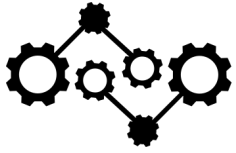
Specific alignment, quick calibration and customization makes the TLNC Nano profiler ideal tool for industrial and production metrology use.

Customization for non-flat components is possible and upon customer request. Other customization is also possible upon request.

### Features

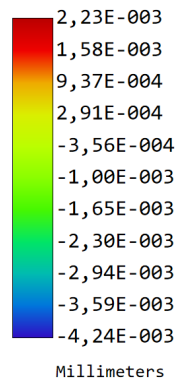
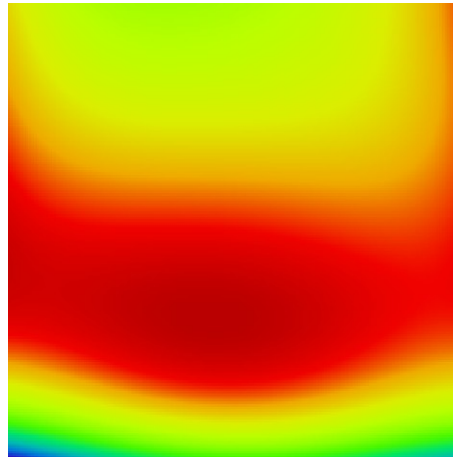
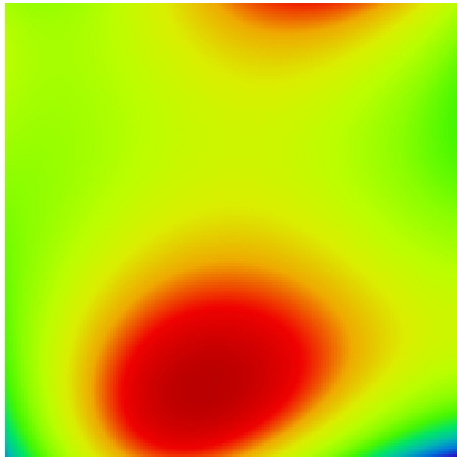
- **Quick & easy non-contact surface profile measurement**
- **No scanning optical profiler** (single-shot operation)
- **Optical component diameter up to 80mm or 55mm square** (customization for maximized resolution)
- **633nm operational wavelength** (other wavelength upon request)
- **Accuracy of down to 200nm**
- **Dynamic range (max. P-V) up to 100μm**





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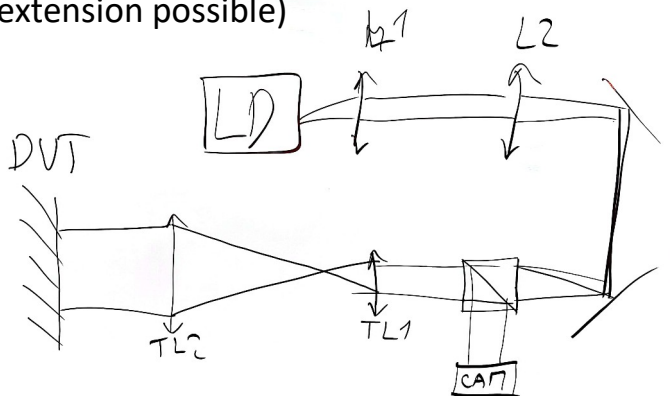
### Measurement examples



Example of two square aluminum coated mirrors with a 50mm dimension showing poor flatness quality ( P-V of  $10\lambda$  @ 633) due to thin substrate.

### Customization

- Operational wavelength (400-900nm, extension possible)
- Optical component diameter
- Reflectivity measurement
- Dynamic range vs. accuracy
- Non-flat components customization
- Possible control system integration (Labview, C )
- Custom reference upon request



### Customization

Please call us for any customization required

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